

**Search Notes**

Application/Control No.

10/577,235

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

HAYASHI ET AL.

Art Unit

1792

**SEARCHED**

Class	Subclass	Date	Examiner
427	251	4/16/2008	BT
427	569	4/16/2008	BT
118	720	4/16/2008	BT
118	723R	4/16/2008	BT
118	730	4/16/2008	BT
118	627	4/16/2008	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventors' name using database in EAST	4/16/2008	BT